

N-Channel Enhancement Mode Power MOSFET

Description

Description	
The HM30N04Q uses advanced trench technology and	
design to provide excellent $R_{\text{DS}(\text{ON})}$ with low gate charge. It	(0) -
can be used in a wide variety of applications.	(2) D
 General Features V_{DS} =40V,I_D =30A R_{DS(ON)} <13mΩ @ V_{GS}=10V High density cell design for ultra low Rdson Fully characterized avalanche voltage and current Good stability and uniformity with high E_{AS} Excellent package for good heat dissipation Special process technology for high ESD capability 	(1) GO (3) S (3) S (3) S
 Application Load switching Hard switched and high frequency circuits Uninterruptible power supply 	S[1 ● 8] D S[2 7] D S[3 6] D G[4 5] D
100% UIS TESTED!	DFN3X3-8L top view
100% ΔVds TESTED!	

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM30N04Q	HM30N04Q	DFN3X3-8L	-	-	-

Absolute Maximum Ratings (T_c=25 $^{\circ}$ Cunless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	Vds	40	V
Gate-Source Voltage	Vgs	±20	V
Drain Current-Continuous	Ι _D	30	А
Drain Current-Continuous(T _C =100℃)	I _D (100℃)	21	A
Pulsed Drain Current	I _{DM}	100	A
Maximum Power Dissipation	PD	65	W
Derating factor		0.43	W /℃
Single pulse avalanche energy (Note 5)	E _{AS}	400	mJ
Operating Junction and Storage Temperature Range	T _J ,T _{STG}	-55 To 175	°C



Thermal Characteristic

Thermal Resistance, Junction-to-Case^(Note 2)

°C**/W**

2.3

R_{ejc}

Electrical Characteristics (Tc=25 $^{\circ}$ C unless otherwise noted)

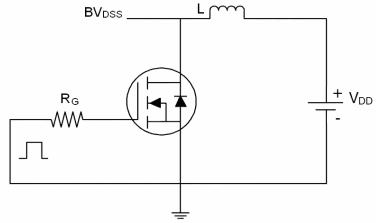
Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics	·					•
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250µA	40	45	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =40V,V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)						
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} ,I _D =250µA	1.2	1.6	2.5	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =20A	-	7.3	13	mΩ
Forward Transconductance	G FS	V _{DS} =10V,I _D =20A	15	-	-	S
Dynamic Characteristics (Note4)						
Input Capacitance	C _{lss}		-	1800	-	PF
Output Capacitance	C _{oss}	V_{DS} =20V, V_{GS} =0V,	-	280	-	PF
Reverse Transfer Capacitance	C _{rss}	F=1.0MHz	-	190	-	PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	t _{d(on)}		-	6.4	_	nS
Turn-on Rise Time	tr	V _{DD} =20V,I _D =2A,R _L =1Ω V _{GS} =10V,R _G =3Ω	-	17.2	-	nS
Turn-Off Delay Time	t _{d(off)}		-	29.6	-	nS
Turn-Off Fall Time	t _f		-	16.8	-	nS
Total Gate Charge	Qg	- V _{DS} =20V,I _D =20A,	-	29		nC
Gate-Source Charge	Q _{gs}		-	4.5		nC
Gate-Drain Charge	Q _{gd}	V _{GS} =10V	-	6.4		nC
Drain-Source Diode Characteristics						
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =10A	-		1.2	V
Diode Forward Current (Note 2)	I _S		-	-	30	Α
Reverse Recovery Time	t _{rr}	TJ = 25°C, IF = 20A	-	29	-	nS
Reverse Recovery Charge	Qrr	di/dt = 100A/µs ^(Note3)	-	26	-	nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD				

Notes:

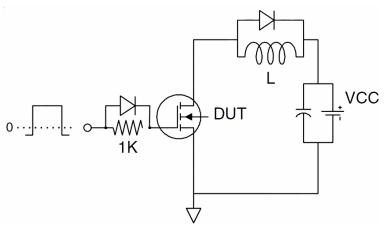
- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board, $t \le 10$ sec.
- **3.** Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2%.
- 4. Guaranteed by design, not subject to production
- **5.** E_{AS} condition : Tj=25 °C, V_{DD} =20V, V_G =10V,L=1mH, Rg=25 Ω ,



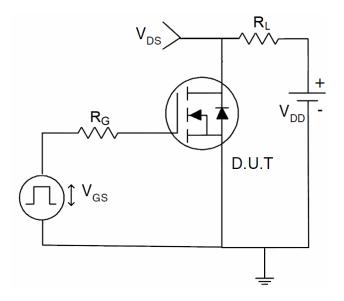
Test circuit 1) E_{AS} Test Circuit



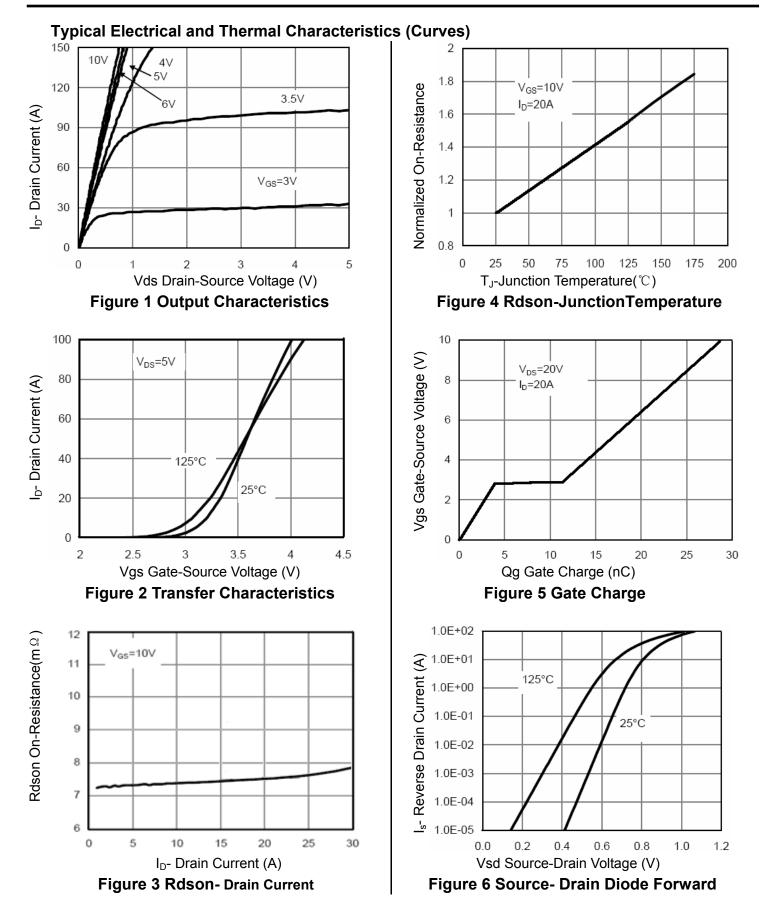
2) Gate Charge Test Circuit



3) Switch Time Test Circuit









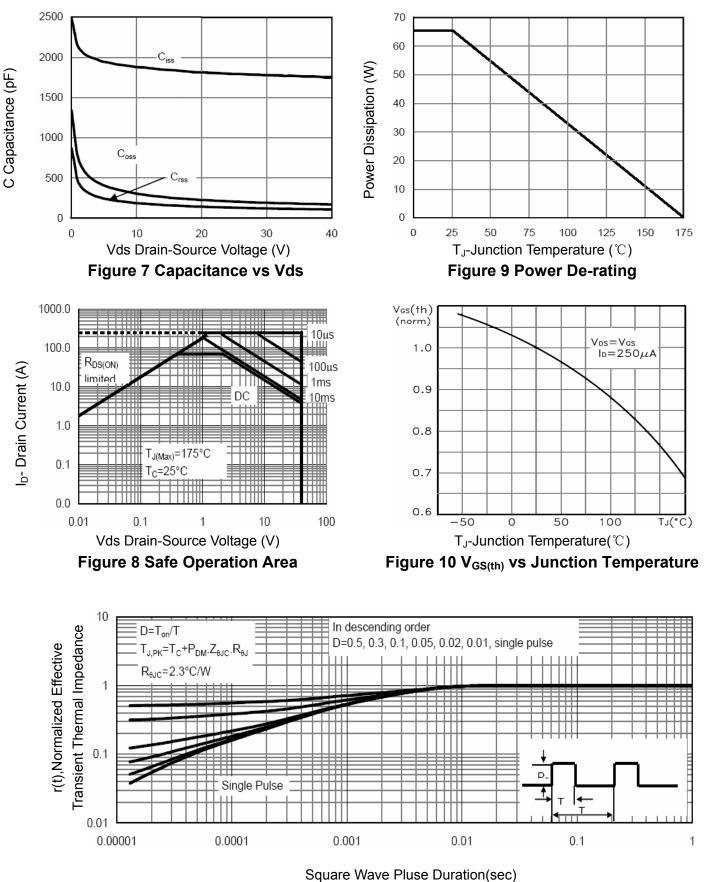


Figure 11 Normalized Maximum Transient Thermal Impedance



NDM

_

10°

0°

12°

10°

٥°

θ1

MAX

0.0354

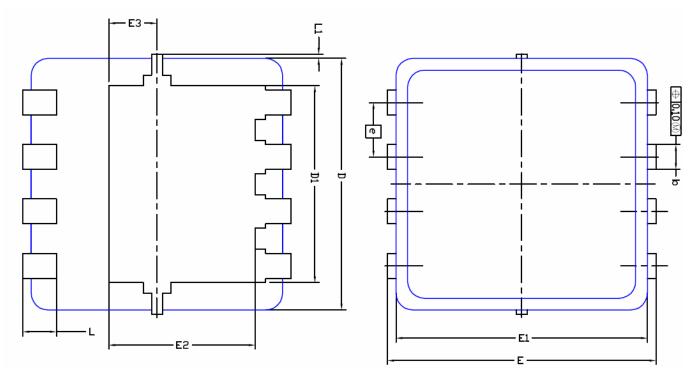
0.002

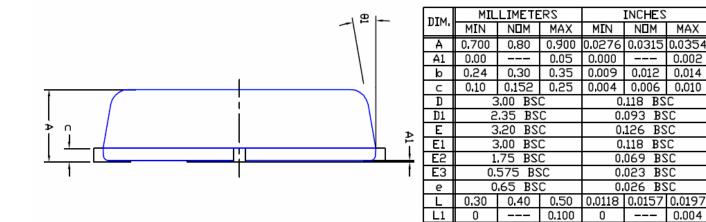
0.014

0.004

12°

DFN3X3 EP Package Information







ATTENTION:

- Any and all H&M SEMI products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life-support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your H&M SEMI representative nearest you before using any H&M SEMI products described or contained herein in such applications.
- H&M SEMI assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all H&M SEMI products described or contained herein.
- Specifications of any and all H&M SEMI products described or contained herein stipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.
- H&M Semiconductor CO.,LTD. strives to supply high-quality high-reliability products. However, any and all semiconductor products fail with some probability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives, that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits and error prevention circuits for safe design, redundant design, and structural design.
- In the event that any or all H&M SEMI products(including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from the authorities concerned in accordance with the above law.
- No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of H&M Semiconductor CO.,LTD.
- Information (including circuit diagrams and circuit parameters) herein is for example only; it is not guaranteed for volume production. H&M SEMI believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.
- Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc. When designing equipment, refer to the "Delivery Specification" for the H&M SEMI product that you intend to use.
- This catalog provides information as of Sep.2010. Specifications and information herein are subject to change without notice.